

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

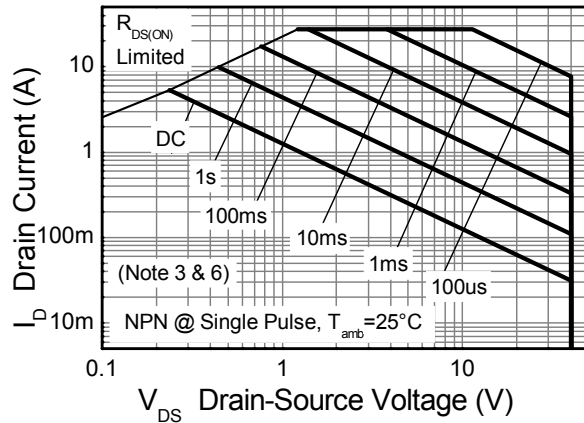
Characteristic			Symbol	N-Channel - Q1	P-Channel - Q2	Units
Drain-Source Voltage			V _{DSS}	40	-40	V
Gate-Source Voltage		(Note 5)	V _{GSS}	±20	±20	V
Continuous Drain Current	V _{GS} = 10V	(Notes 7 & 9)	I _D	7.2	5.2	A
		T _A = 70°C (Notes 7 & 9)		5.5	4.2	
		(Notes 6 & 9)		5.4	4	
		(Notes 6 & 10)		6.5	4.8	
Pulsed Drain Current	V _{GS} = 10V	(Notes 7 & 9)	I _{DM}	27.3	20.4	A
Continuous Source Current (Body diode)		(Notes 7 & 9)	I _S	3.35	3.15	A
Pulsed Source Current (Body diode)		(Notes 8 & 9)	I _{SM}	27.3	20.4	A

Thermal Characteristics (@T_A = +25°C, unless otherwise specified.)

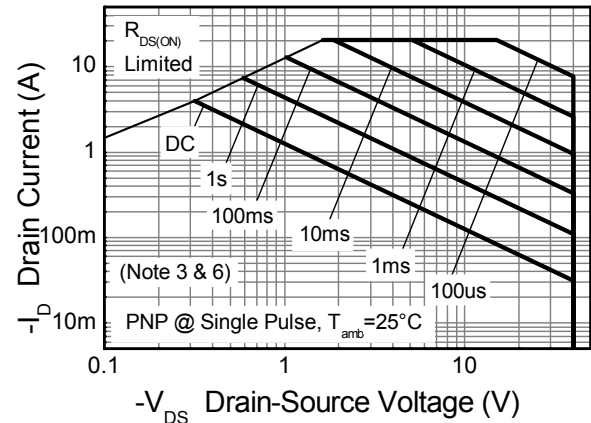
Characteristic		Symbol	N-Channel - Q1	P-Channel - Q2	Unit
Power Dissipation Linear Derating Factor	(Notes 6 & 9)	P _D	1.25 10		W mW/°C
	(Notes 6 & 10)		1.8 14.3		
	(Notes 7 & 9)		2.16 17.2		
	(Notes 6 & 9)		100		
Thermal Resistance, Junction to Ambient	(Notes 6 & 10)	R _{θJA}	70		°C/W
	(Notes 7 & 9)		58		
	(Notes 9 & 11)		53	53	
Thermal Resistance, Junction to Lead		R _{θJL}	53	53	
Operating and Storage Temperature Range		T _J , T _{STG}	-55 to +150		°C

- Notes:
- AEC-Q101 V_{GS} maximum is ±16V.
 - For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
 - Same as note (5), except the device is measured at t ≤ 10 sec.
 - Same as note (5), except the device is pulsed with D= 0.02 and pulse width 300 μs. The pulse current is limited by the maximum junction temperature.
 - For a dual device with one active die.
 - For a device with two active die running at equal power.
 - Thermal resistance from junction to solder-point (at the end of the drain lead).

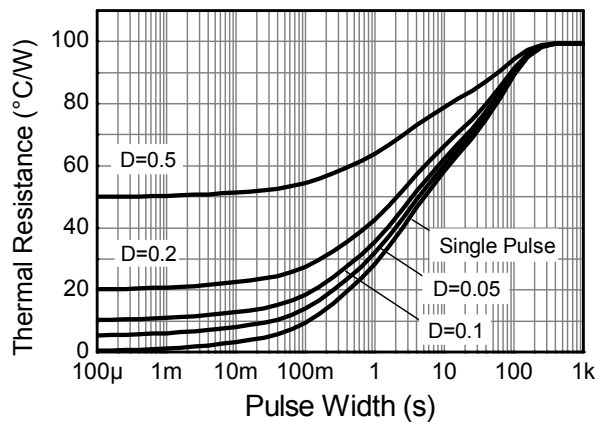
Thermal Characteristics



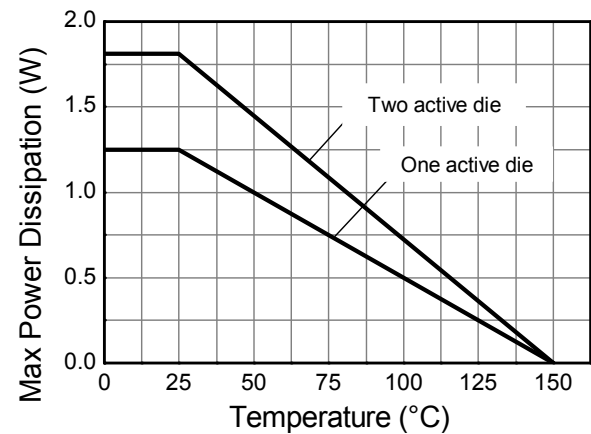
N-channel Safe Operating Area



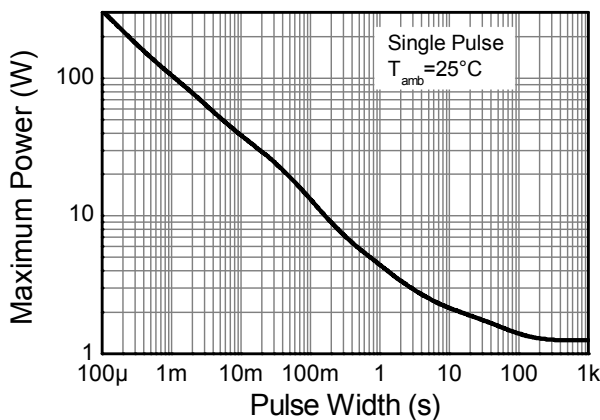
P-channel Safe Operating Area



Transient Thermal Impedance



Derating Curve



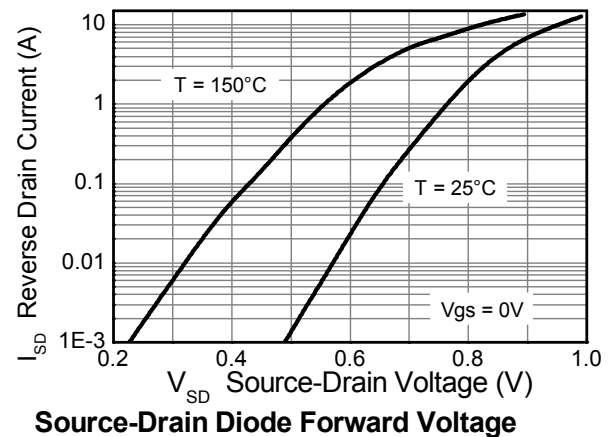
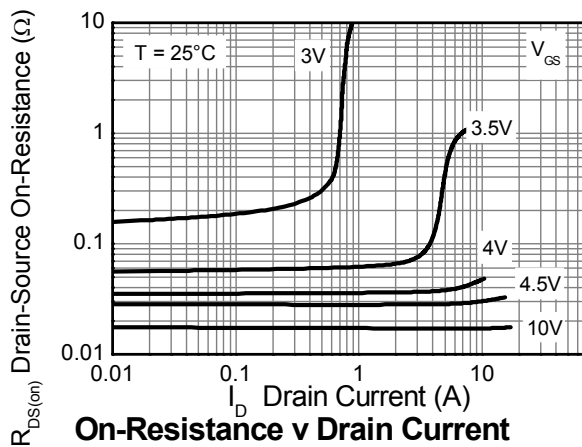
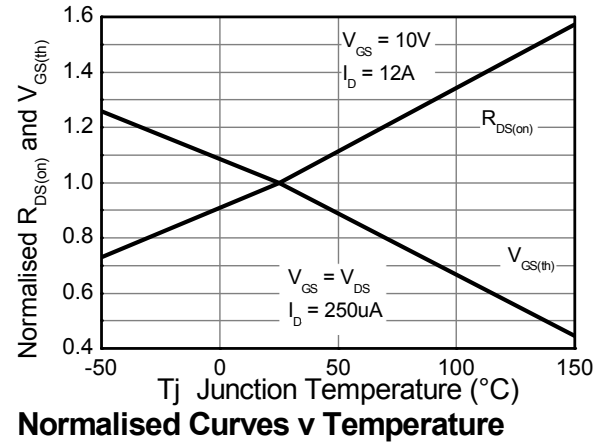
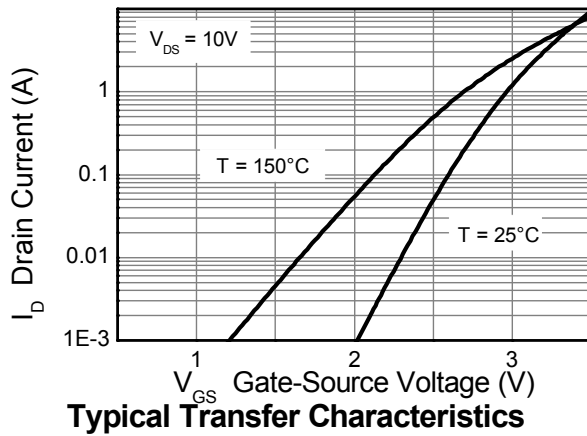
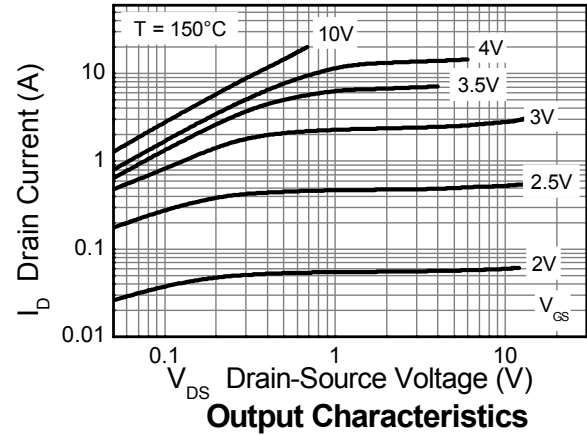
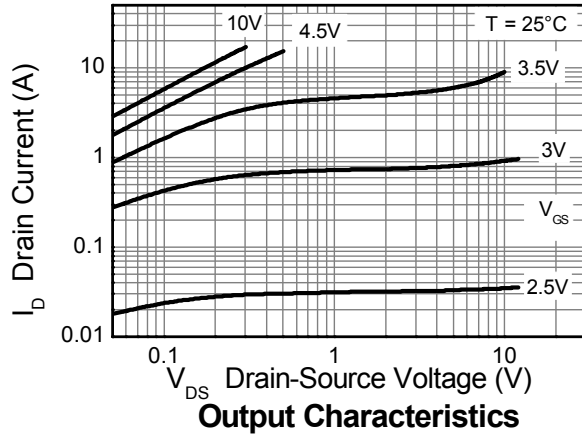
Pulse Power Dissipation

Electrical Characteristics – Q1 N-Channel (@T_A = +25°C, unless otherwise specified.)

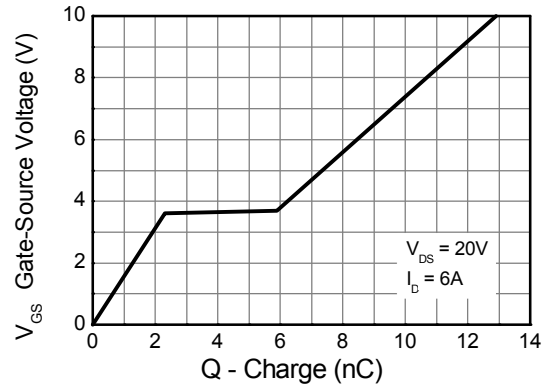
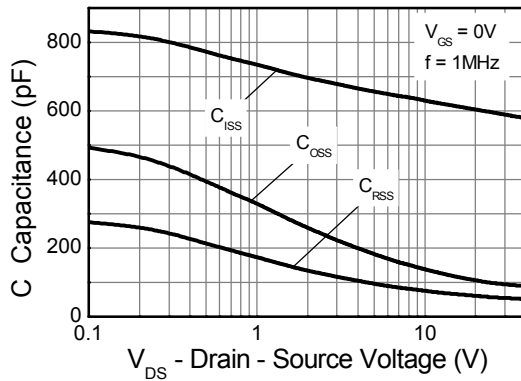
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	40	—	—	V	I _D = 250μA, V _{GS} = 0V	
Zero Gate Voltage Drain Current	I _{DSS}	—	—	0.5	μA	V _{DS} = 40V, V _{GS} = 0V	
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V	
ON CHARACTERISTICS							
Gate Threshold Voltage	V _{GS(th)}	1.0	—	3.0	V	I _D = 250μA, V _{DS} = V _{GS}	
Static Drain-Source On-Resistance (Note 12)	R _{DS (ON)}	—	0.018	0.028	Ω	V _{GS} = 10V, I _D = 6A	
			0.033	0.049		V _{GS} = 4.5V, I _D = 5A	
Forward Transconductance (Notes 12 & 13)	g _{fs}	—	22.8	—	S	V _{DS} = 15V, I _D = 6A	
Diode Forward Voltage (Note 12)	V _{SD}	—	0.845	1.1	V	I _S = 6A, V _{GS} = 0V	
Reverse recovery time (Note 13)	t _{rr}		135	—	ns	I _S = 6A, di/dt = 100A/μs	
Reverse recovery charge (Note 13)	Q _{rr}	—	799	—	nC		
DYNAMIC CHARACTERISTICS (Note 13)							
Input Capacitance	C _{iss}	—	604	—	pF	V _{DS} = 20V, V _{GS} = 0V f = 1MHz	
Output Capacitance	C _{oss}	—	106	—	pF		
Reverse Transfer Capacitance	C _{rss}	—	59.6	—	pF		
Total Gate Charge (Note 14)	Q _g	—	6.5	—	nC	V _{GS} = 4.5V	V _{DS} = 20V I _D = 6A
Total Gate Charge (Note 14)	Q _g	—	12.9	—	nC	V _{GS} = 10V	
Gate-Source Charge (Note 14)	Q _{gs}	—	2.3	—	nC		
Gate-Drain Charge (Note 14)	Q _{gd}	—	3.6	—	nC		
Turn-On Delay Time (Note 14)	t _{D(on)}	—	4.2	—	ns	V _{DD} = 20V, V _{GS} = 10V I _D = 6A, R _G ≅ 6.0Ω	
Turn-On Rise Time (Note 14)	t _r	—	12.4	—	ns		
Turn-Off Delay Time (Note 14)	t _{D(off)}	—	13.8	—	ns		
Turn-Off Fall Time (Note 14)	t _f	—	10.7	—	ns		

Notes: 12. Measured under pulsed conditions. Pulse width ≤ 300μs; duty cycle ≤ 2%
13. For design aid only, not subject to production testing.
14. Switching characteristics are independent of operating junction temperatures.

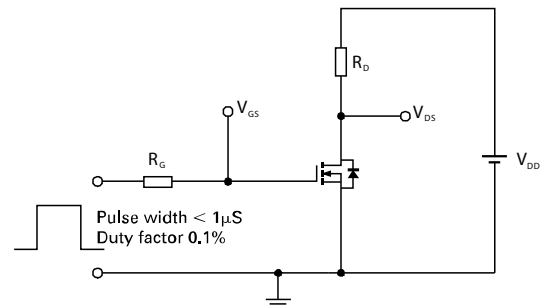
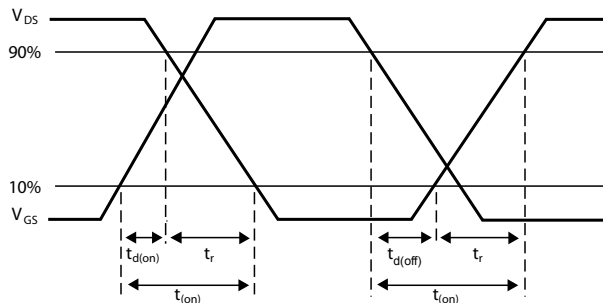
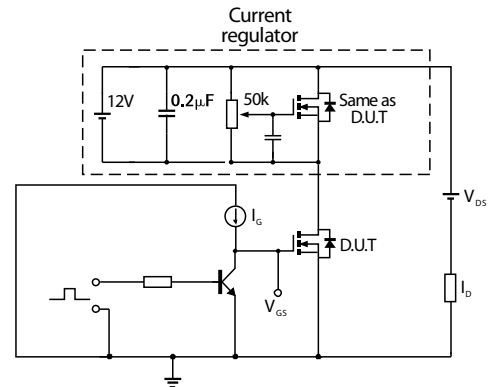
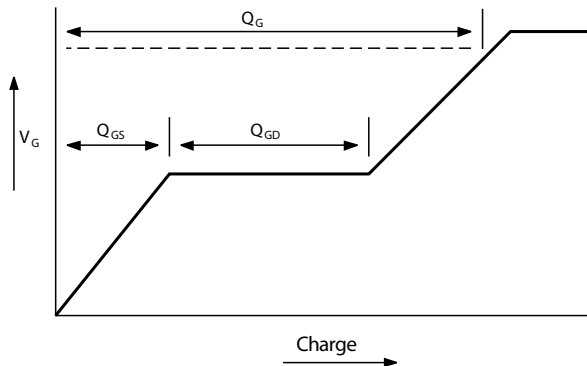
Typical Characteristics – Q1 N-Channel



Typical Characteristics – Q1 N-Channel - (cont.)



Test Circuits – Q1 N-Channel

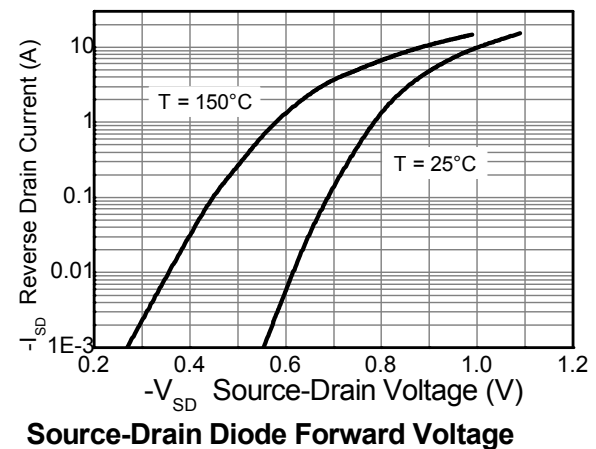
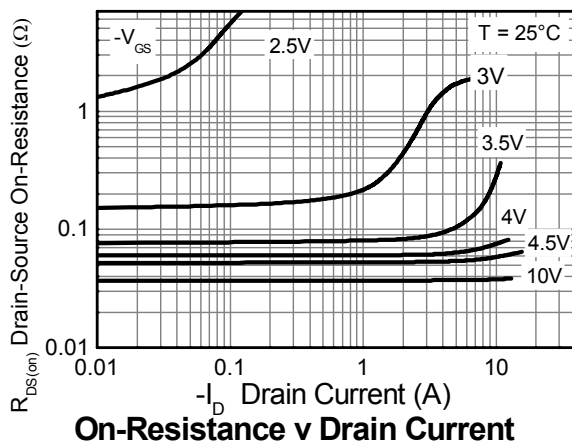
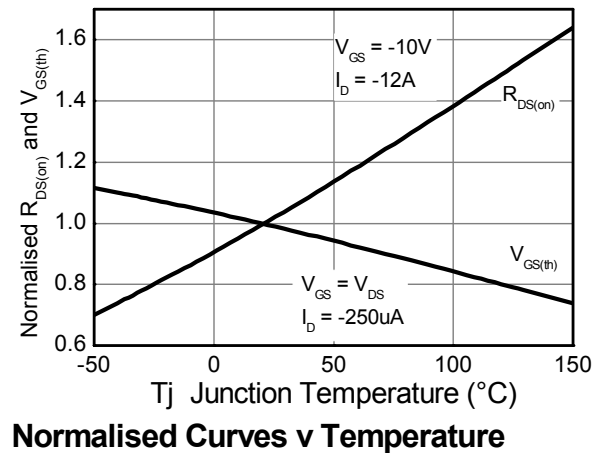
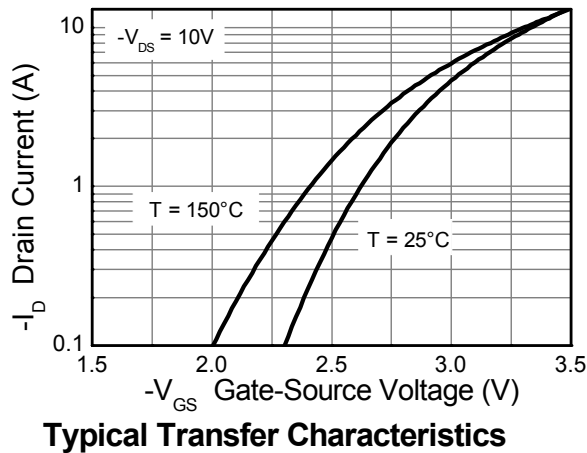
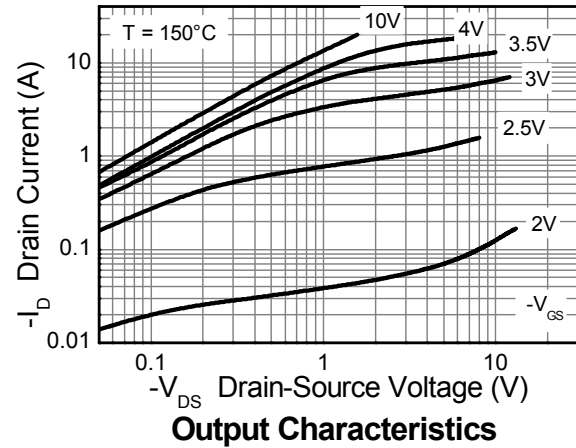
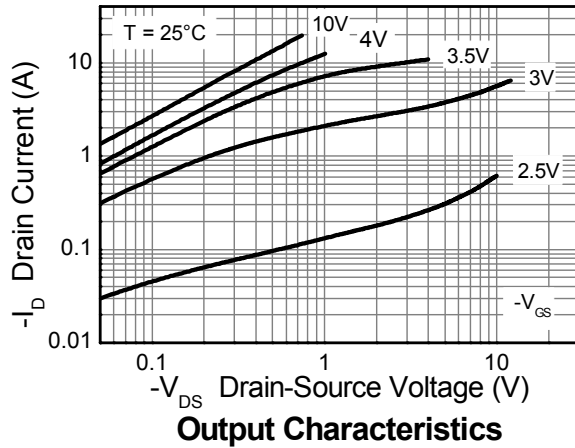


Electrical Characteristics – Q2 P-Channel (@T_A = +25°C, unless otherwise specified.)

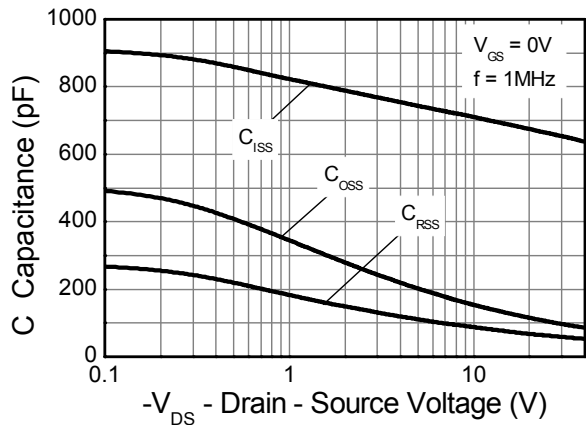
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	-40	—	—	V	I _D = -250 μA, V _{GS} = 0V	
Zero Gate Voltage Drain Current	I _{DSS}	—	—	-0.5	μA	V _{DS} = -40V, V _{GS} = 0V	
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V	
ON CHARACTERISTICS							
Gate Threshold Voltage	V _{GS(th)}	-1.0	—	-3.0	V	I _D = -250 μA, V _{DS} = V _{GS}	
Static Drain-Source On-Resistance (Note 12)	R _{DS(ON)}	—	0.039	0.050	Ω	V _{GS} = -10V, I _D = -6A	
			0.060	0.079		V _{GS} = -4.5V, I _D = -5A	
Forward Transconductance (Notes 12 & 13)	g _{fs}	—	16.6	—	S	V _{DS} = -15V, I _D = -6A	
Diode Forward Voltage (Note 13)	V _{SD}	—	~0.865	-1.1	V	I _S = -6A, V _{GS} = 0V	
Reverse Recovery Time (Note 13)	t _{rr}	—	138	—	ns	I _S = -6A, di/dt = 100A/μs	
Reverse Recovery Charge (Note 13)	Q _{rr}	—	841	—	nC		
DYNAMIC CHARACTERISTICS (Note 13)							
Input Capacitance	C _{iss}	—	674	—	pF	V _{DS} = -20V, V _{GS} = 0V f = 1MHz	
Output Capacitance	C _{oss}	—	115	—	pF		
Reverse Transfer Capacitance	C _{rss}	—	67.7	—	pF		
Total Gate Charge (Note 14)	Q _g	—	7.0	—	nC	V _{GS} = -4.5V	V _{DS} = -20V I _D = -6A
Total Gate Charge (Note 14)	Q _g	—	14	—	nC	V _{GS} = -10V	
Gate-Source Charge (Note 14)	Q _{gs}	—	2.2	—	nC		
Gate-Drain Charge (Note 14)	Q _{gd}	—	3.7	—	nC		
Turn-On Delay Time (Note 14)	t _{D(on)}	—	2.3	—	ns	V _{DD} = -20V, V _{GS} = -10V I _D = -6A, R _G ≅ 6.0Ω	
Turn-On Rise Time (Note 14)	t _r	—	14.1	—	ns		
Turn-Off Delay Time (Note 14)	t _{D(off)}	—	25.1	—	ns		
Turn-Off Fall Time (Note 14)	t _f	—	14.3	—	ns		

Notes: 12. Measured under pulsed conditions. Pulse width ≤ 300μs; duty cycle ≤ 2%
13. For design aid only, not subject to production testing.
14. Switching characteristics are independent of operating junction temperatures.

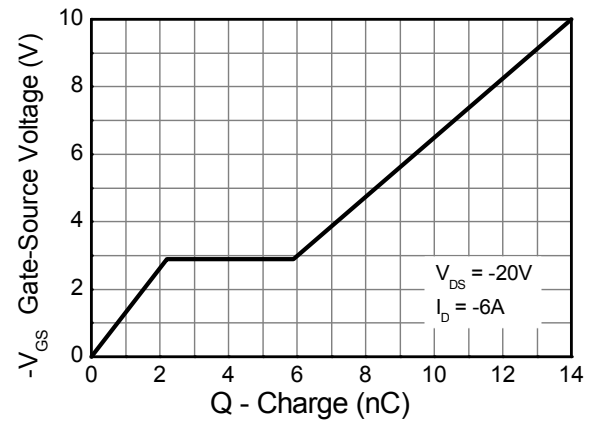
Typical Characteristics – Q2 P-Channel



Typical Characteristics – Q2 P-Channel – (cont.)

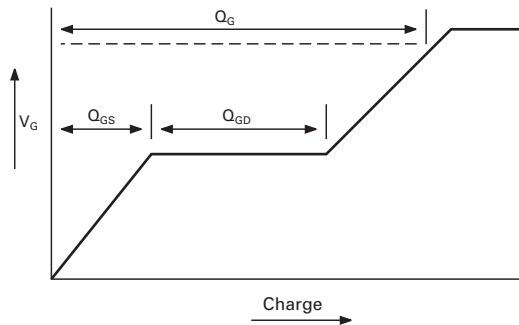


Capacitance v Drain-Source Voltage

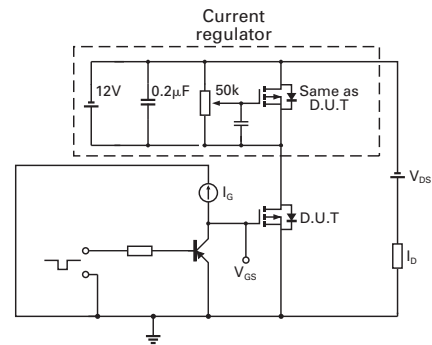


Gate-Source Voltage v Gate Charge

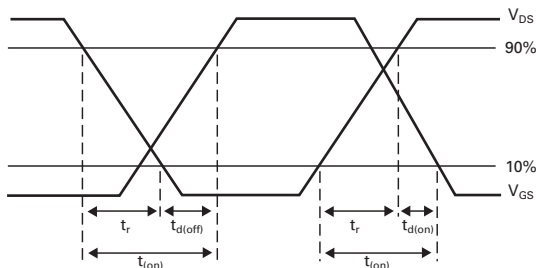
Test Circuits – Q2 P-Channel



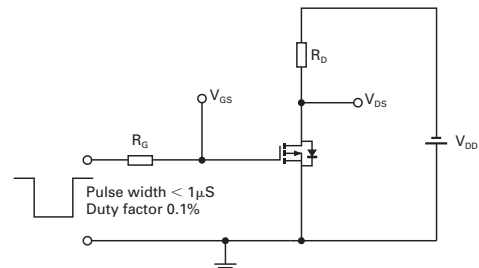
Basic gate charge waveform



Gate charge test circuit



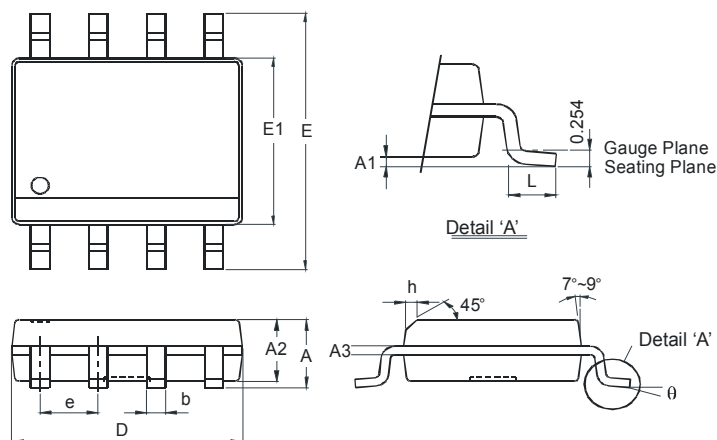
Switching time waveforms



Switching time test circuit

Package Outline Dimensions

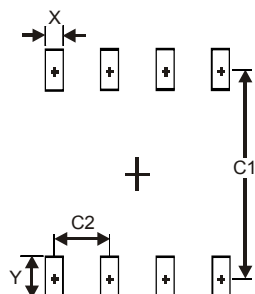
Please see AP02002 at <http://www.diodes.com/datasheets/ap02002.pdf> for latest version.



SO-8		
Dim	Min	Max
A	-	1.75
A1	0.10	0.20
A2	1.30	1.50
A3	0.15	0.25
b	0.3	0.5
D	4.85	4.95
E	5.90	6.10
E1	3.85	3.95
e	1.27 Typ	
h	-	0.35
L	0.62	0.82
θ	0°	8°
All Dimensions in mm		

Suggested Pad Layout

Please see AP02001 at <http://www.diodes.com/datasheets/ap02001.pdf> for the latest version.



Dimensions	Value (in mm)
X	0.60
Y	1.55
C1	5.4
C2	1.27

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